



# Roznov Product Analysis Lab

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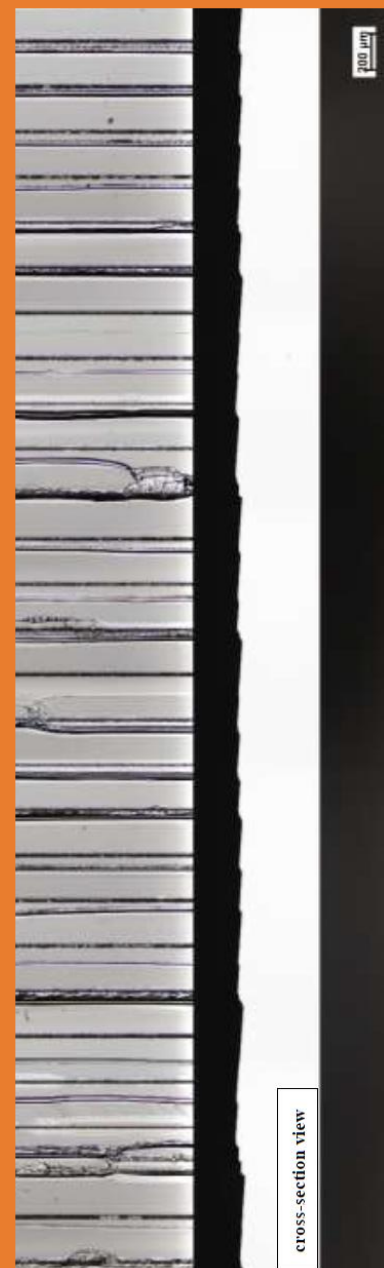
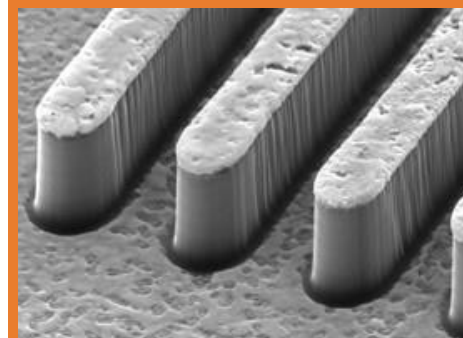
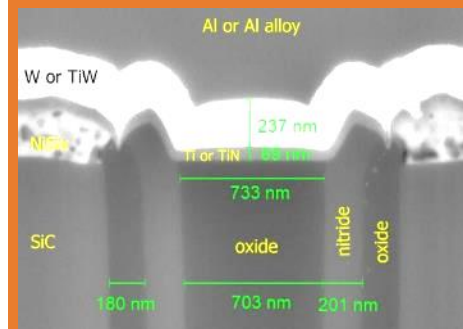
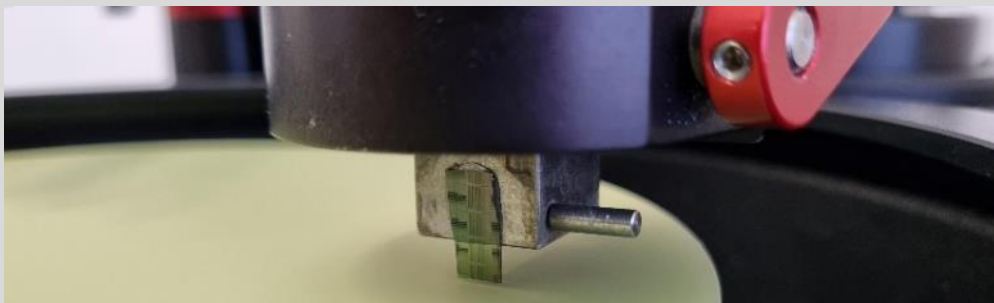
# Physical Analysis

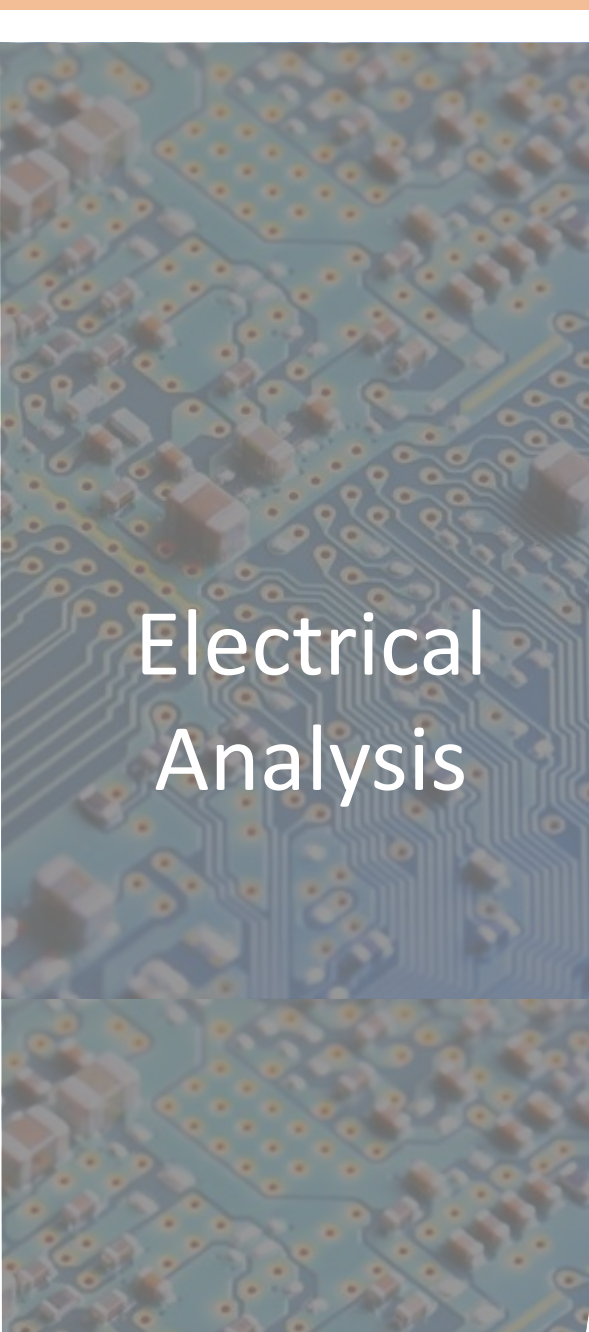
The laboratory fully support the production and development of semiconductor components using the following methods:

- Optical microscopy
- Scanning Electron Microscopy
- Focused ion beam technique
- Cross-Sectional preparation and analysis
- Spreading Resistance Profiling
- Semiconductor delayering
- Semiconductor deprocessing



# Physical Analysis

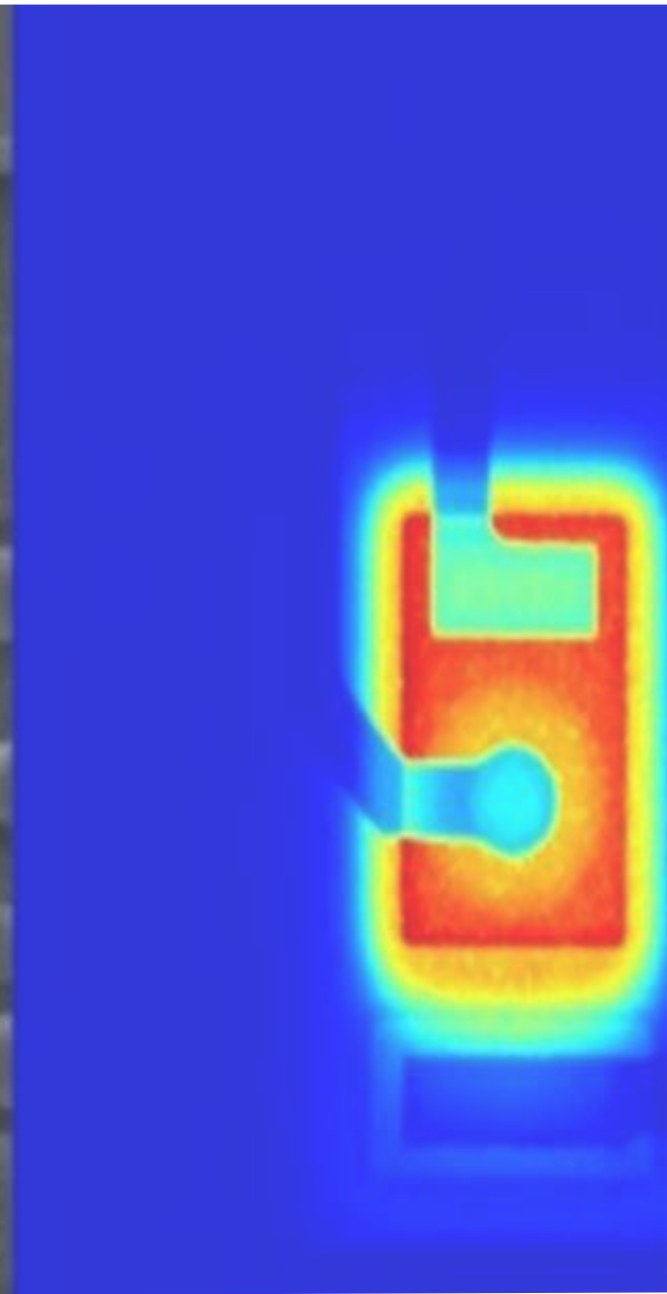




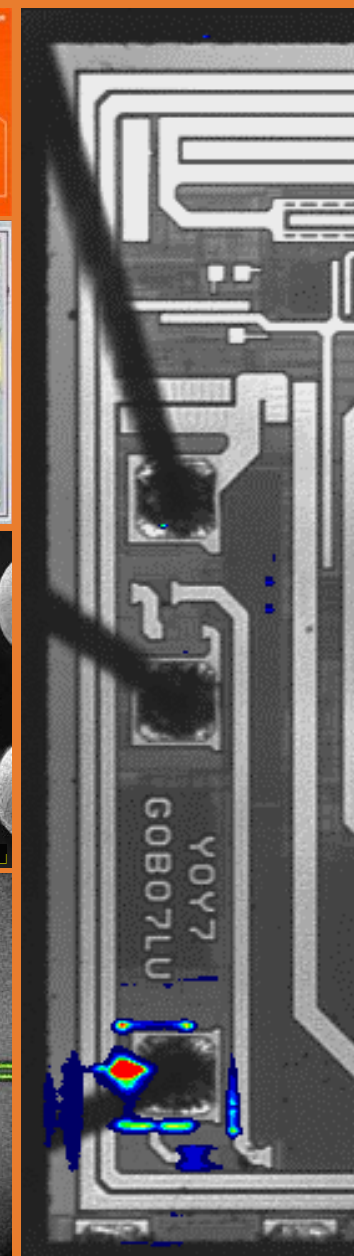
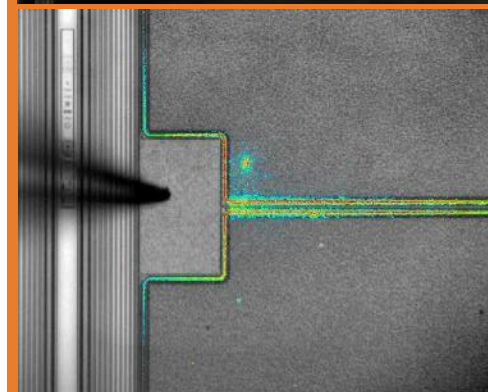
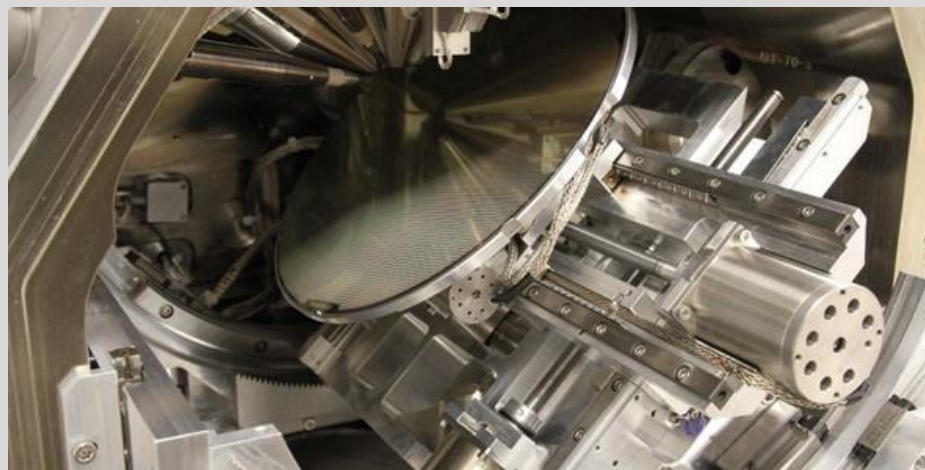
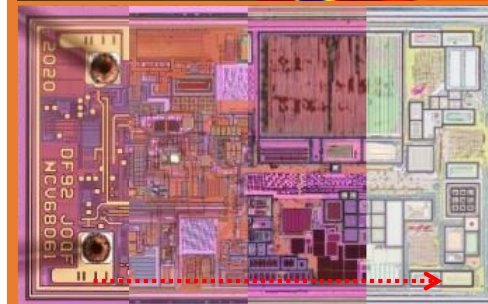
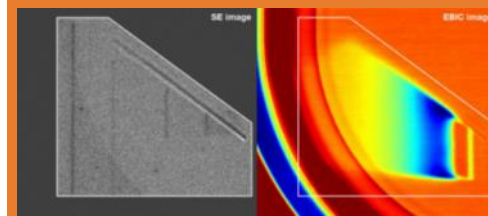
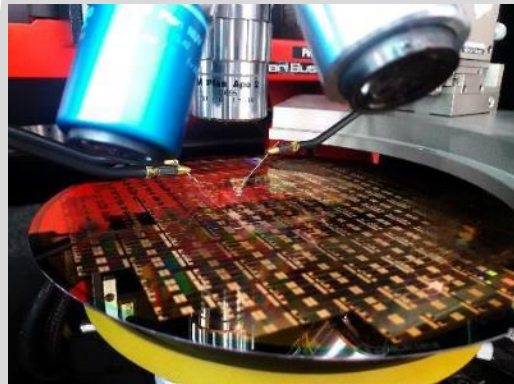
# Electrical Analysis

Electrical analysis provides a benchmark of the component, but also locates defects and faults in the semiconductor component:

- Curve tracing technique
- Competitive Analysis
- Modification of the circuitry of live devices
- Backside and frontside analysis
- IDDQ failure analysis
- Soft/Hard Defect Localization
- Thermal Mapping



# Electrical Analysis



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